Ultramicroscopy 20 (1986) 341–342
North-Holland, Amsterdam

AUTHOR INDEX TO VOLUME 20

Achèche M., C. Colliex, H. Kohl, A. Nourtier and P. Trebbia, Theoretical and experimental study of plasmon excitations in small metallic spheres 20 (1986) 99
Ajayan, P.M., see Marks 20 (1986) 77
Ansaldo, E.J., see Marzke 20 (1986) 161

Barry, J.C., Voidites in diamond – do they contain nitrogen? 20 (1986) 169
Bauer, E., see Poppa 20 (1986) 145
Baumeister, W., see Rachel 20 (1986) 305
Bethge, H., see Meinel 20 (1986) 261
Boudart, M., M.G. Samant and R. Ryoo, Atomic and electronic structure and chemical reactivity of metal clusters 20 (1986) 125
Bovin, J.-O., see Wallenberg 20 (1986) 71
Brewer, J.H., see Marzke 20 (1986) 161
Brown, L.M., Recent applications of STEM to small particles 20 (1986) 39

Colliex, C., see Joyes 20 (1986) 65
Colliex, C., see Achèche 20 (1986) 99

Disko, M.M. and H. Shuman, High spatial resolution analysis using parallel detection EELS 20 (1986) 43
Downing, K.H. and R.M. Glaeser, Improvement in high resolution image quality of radiation-sensitive specimens achieved with reduced spot size of the electron beam 20 (1986) 269
Dundurs, J., see Marks 20 (1986) 77

Fernández-Morán, H., Megavolt and cryo electron microscopy of diamond knife edges 20 (1986) 317
Freund, E., J. Lynch and R. Szymanski, Small particles in the field of industrial supported catalysts 20 (1986) 107

Glaeser, R.M., see Downing 20 (1986) 269
Glaunsinger, W.S., see Long 20 (1986) 15
Guan, R., H. Hashimoto and K.H. Kuo, Use of dynamic electron scattering for studying the position of oxygen atoms in simple metal oxide 20 (1986) 195

Hanai, T., M. Hibino and S. Maruse, Measurement of axial geometrical aberrations of the probe-forming lens by means of the shadow image of fine particles 20 (1986) 329
Harshman, D.R., see Marzke 20 (1986) 161
Hashimoto, H., see Guan 20 (1986) 195
Hawkes, P.W., Meanwhile, towards the end of the decade ... 20 (1986) 189
Hegerl, R., see Rachel 20 (1986) 305
Heinemann, K. and F. Soria, On the detection and size classification of nanometer-size metal particles on amorphous substrates 20 (1986) 1
Heydenreich, J., see Hillebrand 20 (1986) 279
Hibino, M., see Hanai 20 (1986) 329
Hillebrand, R., K. Scheerschmidt and J. Heydenreich, Computer simulation of diffraction contrast images and lattice fringe patterns of small hexagonal dislocation loops 20 (1986) 279
Hoppe, W. and H. Tietz, Criteria for the comparison of electron microscopical 3D reconstructions of individual particles 20 (1986) 217

Jakubowski, U., see Rachel 20 (1986) 305
Jena, P., see Rao 20 (1986) 51
Joyes, P., J. Van de Walle and C. Colliex, About the stability and structure of metallic clusters produced by a LMIS 20 (1986) 65

Keitel, R., see Marzke 20 (1986) 161
Khanna, S.N., see Rao 20 (1986) 51
Klaua, M., see Meinel 20 (1986) 261
Kohl, H., see Achèche 20 (1986) 99
Kuo, K.H., see Guan 20 (1986) 195

Lambert, L., Some anecdotes around and with Colonel Ernst August Ruska 20 (1986) 337
Lichte, H., Electron holography approaching atomic resolution 20 (1986) 293
Limm, W., see Moskovits 20 (1986) 83
Long, N.J., R.F. Marzke, M. McKelvy and W.S. Glaunsinger, Characterization of Pt microcrystals using high resolution electron microscopy 20 (1986) 15
Long, N.J. and A.K. Petford-Long, In-situ electron-beam-induced reduction of CuO: a study of phase transformations in cupric oxide 20 (1986) 151
Lyman, C.E., Digital X-ray imaging of small particles 20 (1986) 119
Lynch, J., see Freund 20 (1986) 107

Marks, L.D., P.M. Ajayan and J. Dundurs, Quasi-melting of small particles 20 (1986) 77
Martin, P.L., see Menon 20 (1986) 93
Maruse, S., see Hanai 20 (1986) 329
Marzke, R.F., see Long 20 (1986) 15
Marzke, R.F., D.R. Harshman, E.J. Ansaldo, R. Keitel, M. Senba, D.R. Noakes and J.H. Brewer, The relaxation rate of muonium as a function of temperature and loading in silica-supported platinum catalysts 20 (1986) 161
McKelvy, M., see Long 20 (1986) 15
Meinel, K., M. Klaua and H. Bethge, TEM and AES investigations of surface-diffusion-induced aging processes in thin Au films on Ag(111) 20 (1986) 261
Menon, S.K. and P.L. Martin, Determination of the anisotropy of surface free energy of fine metal particles 20 (1986) 93
Moskovits, M. and W. Limm, Spectroscopic studies of metal clusters: absorption and resonance Raman spectroscopy of Nb_2 20 (1986) 83

Noakes, D.R., see Marzke 20 (1986) 161
Nourtier, A., see Achèche 20 (1986) 99

Papageorgopoulos, C.A., see Poppa 20 (1986) 145
Petford-Long, A.K., see Wallenberg 20 (1986) 71
Petford-Long, A.K., see Long 20 (1986) 151
Poppa, H., C.A. Papageorgopoulos and E. Bauer, The low-rate growth of particulate Fe on planar alumina supports 20 (1986) 145

Rachel, R., U. Jakubowski, H. Tietz, R. Hegerl and W. Baumeister, Projected structure of the surface protein of Deinococcus radiodurans determined to 8 Å resolution by cryomicroscopy 20 (1986) 305
Rao, B.K., S.N. Khanna and P. Jena, Ab initio studies of the electronic structure of micro-clusters 20 (1986) 51
Rose, H., see Schönecker 20 (1986) 203
Ross, P.N., see Sattler 20 (1986) 21
Ryoo, R., see Boudart 20 (1986) 125

Sachtler, W.M.H., Morphology and crystal face specificity of catalysis on small particles 20 (1986) 135
Samant, M.G., see Boudart 20 (1986) 125
Sanders, J.V., Structure of catalytic particles 20 (1986) 33
Sattler, K., Clusters in beams 20 (1986) 55
Sattler, M.L. and P.N. Ross, The surface structure of Pt crystallites supported on carbon black 20 (1986) 21
Scheerschmidt, K., see Hillebrand 20 (1986) 279
Schimmel, G., The succession of generations of electron microscopists 20 (1986) 183
Schönecker, G., H. Rose and R. Spehr, Fast charge-simulation procedure for determining the electron-optical properties of electrostatic systems 20 (1986) 203
Senba, M., see Marzke 20 (1986) 161
Shuman, H., see Disko 20 (1986) 43
Smith, D.J., Foreword 20 (1986) ix
Smith, D.J., see Wallenberg 20 (1986) 71
Soria, F., see Heinemann 20 (1986) 1
Spehr, R., see Schönecker 20 (1986) 203
Szymanski, R., see Freund 20 (1986) 107

Thomas, G., Some applications of electron microscopy in materials science 20 (1986) 239
Tietz, H., see Hoppe 20 (1986) 217
Tietz, H., see Rachel 20 (1986) 305
Trebbia, P., see Achèche 20 (1986) 99

Uyeda, R., Experiments with fine-particle beams 20 (1986) 29
Van de Walle, J., see Joyes 20 (1986) 65

Wallenberg, L.R., J.-O. Bovin, A.K. Petford-Long and D.J. Smith, Atomic-resolution study of structural rearrangements in small platinum crystals 20 (1986) 71

Ultramicroscopy 20 (1986) 343–344
North-Holland, Amsterdam

SUBJECT INDEX TO VOLUME 20

Analytical microscopy
Atomic structure and properties of small particles, ASU Workshop, January 1986, *Ed. Smith* 20 (1986) ix
Voidites in diamond – do they contain nitrogen? *Barry* 20 (1986) 169
Use of dynamic electron scattering for studying the position of oxygen atoms in simple metal oxide, *Guan, Hashimoto and Kuo* 20 (1986) 195
Some applications of electron microscopy in materials science, *Thomas* 20 (1986) 239
TEM and AES investigations of surface-diffusion-induced aging processes in thin Au films on Ag(111), *Meinel, Klaua and Bethge* 20 (1986) 261

Conventional electron microscopy
The succession of generations of electron microscopists, *Schimmel* 20 (1986) 183
Some applications of electron microscopy in materials science, *Thomas* 20 (1986) 239

Cryo electron microscopy
Projected structure of the surface protein of Deinococcus radiodurans determined to 8 Å resolution by cryomicroscopy, *Rachel, Jakubowski, Tietz, Hegerl and Baumeister* 20 (1986) 305
Megavolt and cryo electron microscopy of diamond knife edges, *Fernandez-Morán* 20 (1986) 317

Diffraction and optical diffraction
Computer simulation of diffraction contrast images and lattice fringe patterns of small hexagonal dislocation loops, *Hillebrand, Scheerschmidt and Heydenreich* 20 (1986) 279

Electron energy loss spectroscopy
High spatial resolution analysis using parallel detection EELS, *Disko and Shuman* 20 (1986) 43
Theoretical and experimental study of plasmon excitations in small metallic spheres, *Achèche, Colliex, Kohl, Nourtier and Trebbia* 20 (1986) 99

High resolution
Atomic structure and properties of small particles, ASU Workshop, January 1986, *Ed. Smith* 20 (1986) ix
Characterization of Pt microcrystals using high resolution electron microscopy, *Long, Marzke, McKelvy and Glaunsinger* 20 (1986) 15
High spatial resolution analysis using parallel detection EELS, *Disko and Shuman* 20 (1986) 43
Atomic-resolution study of structural rearrangements in small platinum crystals, *Wallenberg, Bovin, Petford-Long and Smith* 20 (1986) 71
Electron holography approaching atomic resolution, *Lichte* 20 (1986) 293

High voltage
Some applications of electron microscopy in materials science, *Thomas* 20 (1986) 239
Megavolt and cryo electron microscopy of diamond knife edges, *Fernandez-Morán* 20 (1986) 317

History
The succession of generations of electron microscopists, *Schimmel* 20 (1986) 183
Meanwhile, towards the end of the decade ..., *Hawkes* 20 (1986) 189
Some anecdotes around and with Colonel Ernst August Ruska, *Lambert* 20 (1986) 337

Image processing, 3D reconstruction
Criteria for the comparison of electron microscopical 3D reconstructions of individual particles, *Hoppe and Tietz* 20 (1986) 217
Electron holography approaching atomic resolution, *Lichte* 20 (1986) 293
Projected structure of the surface protein of Deinococcus radiodurans determined to 8 Å resolution by cryomicroscopy, *Rachel, Jakubowksi, Tietz, Hegerl and Baumeister* 20 (1986) 305

Imaging
Improvement in high resolution image quality of radiation-sensitive specimens achieved with reduced spot size of the electron beam, *Downing and Glaeser* 20 (1986) 269
Electron holography approaching atomic resolution, *Lichte* 20 (1986) 293
Measurement of axial geometrical aberrations of the probe-forming lens by means of the shadow image of fine particles, *Hanai, Hibino and Maruse* 20 (1986) 329

Instrumentation

High spatial resolution analysis using parallel detection EELS, *Disko and Shuman* 20 (1986) 43

Methods and techniques

Fast charge-simulation procedure for determining the electron-optical properties of electrostatic systems, *Schönecker, Rose and Spehr* 20 (1986) 203

Measurement of axial geometrical aberrations of the probe-forming lens by means of the shadow image of fine particles, *Hanai, Hibino and Maruse* 20 (1986) 329

Particle optics, theory

Meanwhile, towards the end of the decade ..., *Hawkes* 20 (1986) 189

Fast charge-simulation procedure for determining the electron-optical properties of electrostatic systems, *Schönecker, Rose and Spehr* 20 (1986) 203

Radiation damage and contamination

Improvement in high resolution image quality of radiation-sensitive specimens achieved with reduced spot size of the electron beam, *Downing and Glaeser* 20 (1986) 269

Scanning transmission electron microscopy

Recent applications of STEM to small particles, *Brown* 20 (1986) 39

Surfaces, clusters, interfaces and particles

Atomic structure and properties of small particles, ASU Workshop, January 1986, *Ed. Smith* 20 (1986) ix

On the detection and size classification of nanometer-size metal particles on amorphous substrates, *Heinemann and Soria* 20 (1986) 1

Characterization of Pt microcrystals using high resolution electron microscopy, *Long, Marzke, McKelvy and Glaunsinger* 20 (1986) 15

The surface structure of Pt crystallites supported on carbon black, *Sattler and Ross* 20 (1986) 21

Experiments with fine-particle beams, *Uyeda* 20 (1986) 29

Structure of catalytic particles, *Sanders* 20 (1986) 33

Recent applications of STEM to small particles, *Brown* 20 (1986) 39

Ab initio studies of the electronic structure of micro-clusters, *Rao, Khanna and Jena* 20 (1986) 51

Clusters in beams, *Sattler* 20 (1986) 55

About the stability and structure of metallic clusters produced by a LMIS, *Joyes, Van de Walle and Colliex* 20 (1986) 65

Atomic-resolution study of structural rearrangements in small platinum crystals, *Wallenberg, Bovin, Petford-Long and Smith* 20 (1986) 71

Quasi-melting of small particles, *Marks, Ajayan and Dundurs* 20 (1986) 77

Spectroscopic studies of metal clusters: absorption and resonance Raman spectroscopy of Nb_2, *Moskovits and Limm* 20 (1986) 83

Determination of the anisotropy of surface free energy of fine metal particles, *Menon and Martin* 20 (1986) 93

Theoretical and experimental study of plasmon excitations in small metallic spheres, *Achèche, Colliex, Kohl, Nourtier and Trebbia* 20 (1986) 99

Small particles in the field of industrial supported catalysts, *Freund, Lynch and Szymanski* 20 (1986) 107

Digital X-ray imaging of small particles, *Lyman* 20 (1986) 119

Atomic and electronic structure and chemical reactivity of metal clusters, *Boudart, Samant and Ryoo* 20 (1986) 125

Morphology and crystal face specificity of catalysis on small particles, *Sachtler* 20 (1986) 135

The low-rate growth of particulate Fe on planar alumina supports, *Poppa, Papageorgopoulos and Bauer* 20 (1986) 145

In-situe electron-beam-induced reduction of CuO; a study of phase transformations in cupric oxide, *Long and Petford-Lung* 20 (1986) 151

The relaxation rate of muonium as a function of temperature and loading in silica-supported platinum catalysis, *Marzke, Harshman, Ansaldo, Keitel, Senba, Noakes and Brewer* 20 (1986) 161

Use of dynamic electron scattering for studying the position of oxygen atoms in simple metal oxide, *Guan, Hashimoto and Kuo* 20 (1986) 195

TEM and AES investigations of surface-diffusion-induced aging processes in thin Au films on Ag(111), *Meinel, Klaua and Bethge* 20 (1986) 261

Projected structure of the surface protein of Deinococcus radiodurans determined to 8 Å resolution by cryomicroscopy, *Rachel, Jakubowski, Tietz, Hegerl and Baumeister* 20 (1986) 305